

HAF2001

Silicon N Channel MOS FET Series
Power Switching

HITACHI

ADE-208-353 D (Z)

5th. Edition

October 1997

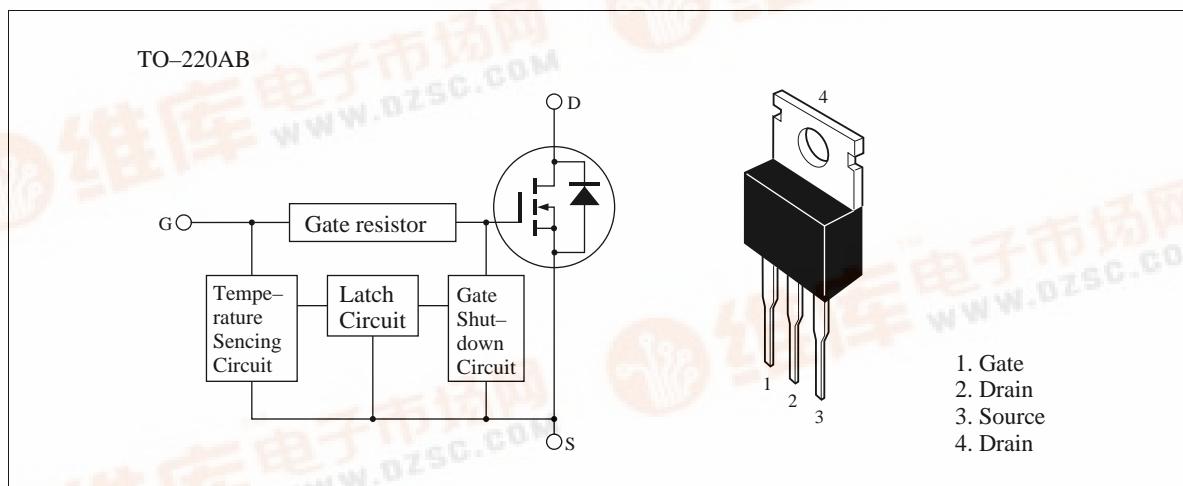
Features

This FET has the over temperature shut-down capability sensing to the junction temperature.

This FET has the built-in over temperature shut-down circuit in the gate area. And this circuit operation to shut-down the gate voltage in case of high junction temperature like applying over power consumption, over current etc.

- Logic level operation (4 to 6 V Gate drive)
- High endurance capability against to the short circuit
- Built-in the over temperature shut-down circuit
- Latch type shut-down operation (Need 0 voltage recovery)

Outline



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Absolute Maximum Ratings (Ta = 25°C)

Item	Symbol	Ratings	Unit
Drain to source voltage	V _{DSS}	60	V
Gate to source voltage	V _{GSS}	16	V
Gate to source voltage	V _{GSS}	-2.8	V
Drain current	I _D	20	A
Drain peak current	I _{D(pulse)} ^{Note1}	40	A
Body-drain diode reverse drain current	I _{DR}	20	A
Channel dissipation	P _{ch} ^{Note2}	50	W
Channel temperature	T _{ch}	150	°C
Storage temperature	T _{stg}	-55 to +150	°C

Note: 1. PW ≤ 10μs, duty cycle ≤ 1 %
2. Value at Ta = 25°C

Typical Operation Characteristics

Item	Symbol	Min	Typ	Max	Unit	Test Conditions
Input voltage	V _{IH}	3.5	—	—	V	
	V _{IL}	—	—	1.2	V	
Input current (Gate non shut down)	I _{IH1}	—	—	100	μA	Vi = 8V, V _{DS} = 0
	I _{IH2}	—	—	50	μA	Vi = 3.5V, V _{DS} = 0
	I _{IL}	—	—	1	μA	Vi = 1.2V, V _{DS} = 0
Input current (Gate shut down)	I _{IH(sd)1}	—	0.8	—	mA	Vi = 8V, V _{DS} = 0
	I _{IH(sd)2}	—	0.35	—	mA	Vi = 3.5V, V _{DS} = 0
Shut down temperature	T _{sd}	—	175	—	°C	Channel temperature
Gate operation voltage	V _{OP}	3.5	—	13	V	

Electrical Characteristics (Ta = 25°C)

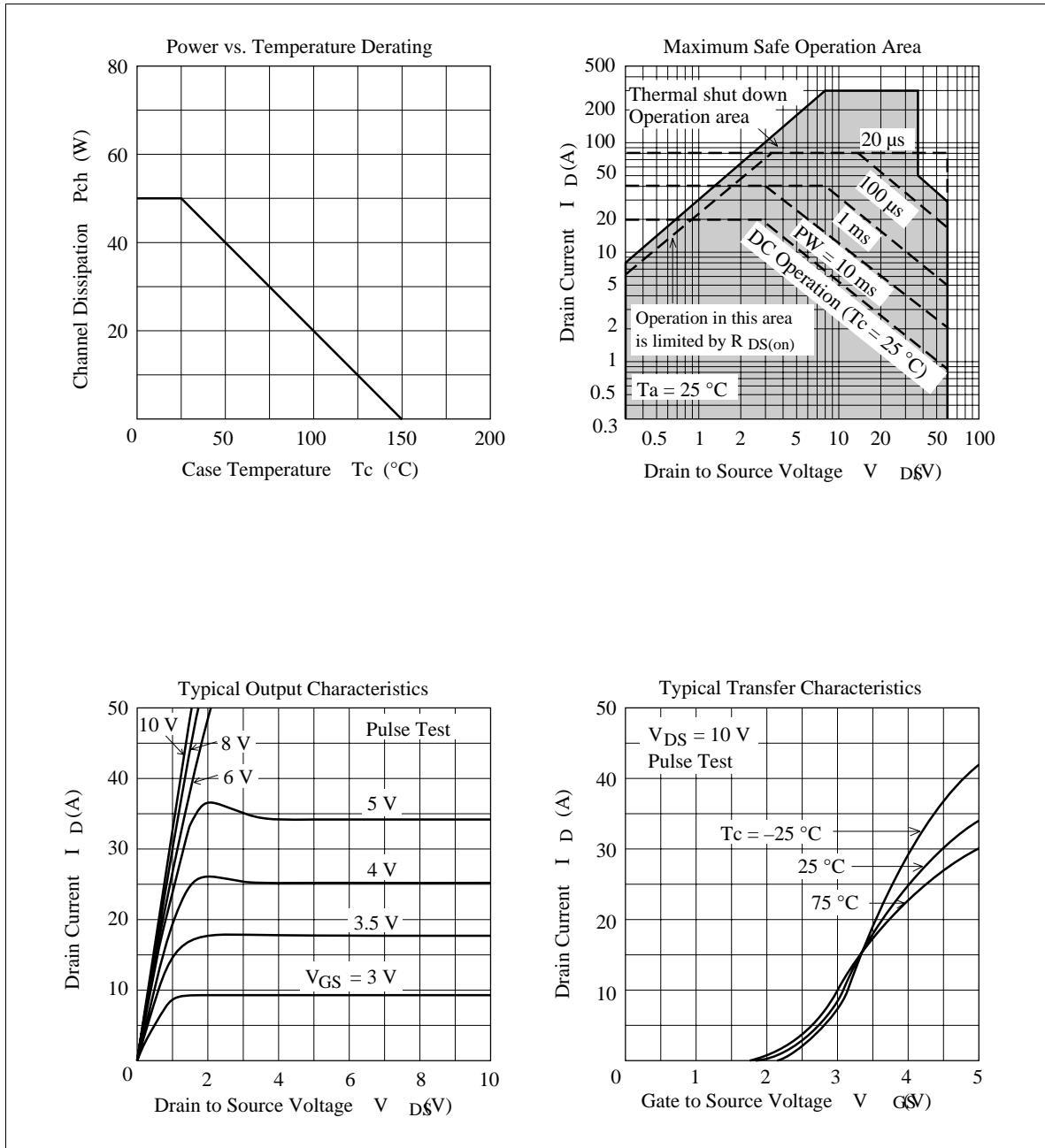
Item	Symbol	Min	Typ	Max	Unit	Test Conditions
Drain current	I _{D1}	10	—	—	A	V _{GS} = 3.5V, V _{DS} = 2V
Drain current	I _{D2}	—	—	10	mA	V _{GS} = 1.2V, V _{DS} = 2V
Drain to source breakdown voltage	V _{(BR)DSS}	60	—	—	V	I _D = 10mA, V _{GS} = 0
Gate to source breakdown voltage	V _{(BR)GSS}	16	—	—	V	I _G = 100μA, V _{DS} = 0
Gate to source breakdown voltage	V _{(BR)GSS}	-2.8	—	—	V	I _G = -100μA, V _{DS} = 0
Gate to source leak current	I _{GSS1}	—	—	100	μA	V _{GS} = 8V, V _{DS} = 0
	I _{GSS2}	—	—	50	μA	V _{GS} = 3.5V, V _{DS} = 0
	I _{GSS3}	—	—	1	μA	V _{GS} = 1.2V, V _{DS} = 0
	I _{GSS4}	—	—	-100	μA	V _{GS} = -2.4V, V _{DS} = 0
Input current (shut down)	I _{GS(op)1}	—	0.8	—	mA	V _{GS} = 8V, V _{DS} = 0
	I _{GS(op)2}	—	0.35	—	mA	V _{GS} = 3.5V, V _{DS} = 0
Zero gate voltage drain current	I _{DSS}	—	—	250	μA	V _{DS} = 50 V, V _{GS} = 0
Gate to source cutoff voltage	V _{GS(off)}	1.0	—	2.25	V	I _D = 1mA, V _{DS} = 10V
Static drain to source on state resistance	R _{DS(on)}	—	50	65	mΩ	I _D = 10A, V _{GS} = 4V ^{Note3}
Static drain to source on state resistance	R _{DS(on)}	—	30	43	mΩ	I _D = 10A, V _{GS} = 10V ^{Note3}
Forward transfer admittance	y _{fs}	6	12	—	S	I _D = 10A, V _{DS} = 10V ^{Note3}
Output capacitance	C _{oss}	—	630	—	pF	V _{DS} = 10V, V _{GS} = 0 f = 1 MHz
Turn-on delay time	t _{d(on)}	—	7.5	—	μs	I _D = 5A, V _{GS} = 5V
Rise time	t _r	—	29	—	μs	R _L = 6Ω
Turn-off delay time	t _{d(off)}	—	34	—	μs	
Fall time	t _f	—	26	—	μs	
Body-drain diode forward voltage	V _{DF}	—	1.0	—	V	I _F = 20A, V _{GS} = 0
Body-drain diode reverse recovery time	t _{rr}	—	110	—	ns	I _F = 20A, V _{GS} = 0 diF/ dt = 50A/μs
Over load shut down operation time ^{Note4}	t _{os1}	—	1.8	—	ms	V _{GS} = 5V, V _{DD} = 12V
	t _{os2}	—	0.7	—	ms	V _{GS} = 5V, V _{DD} = 24V

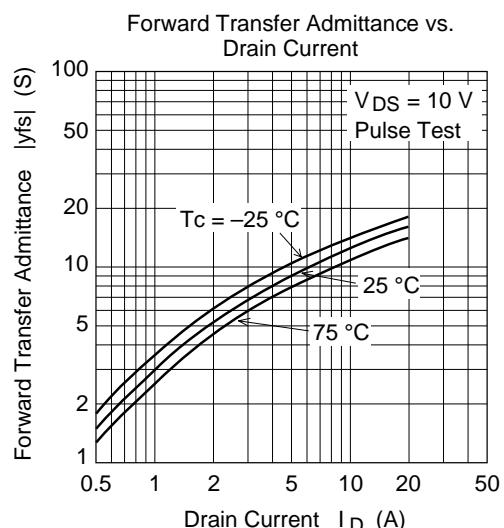
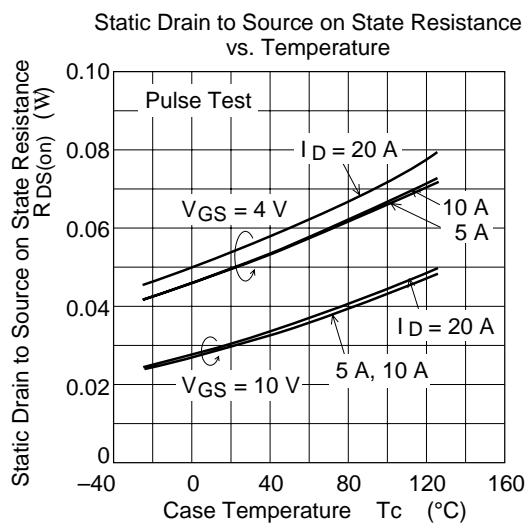
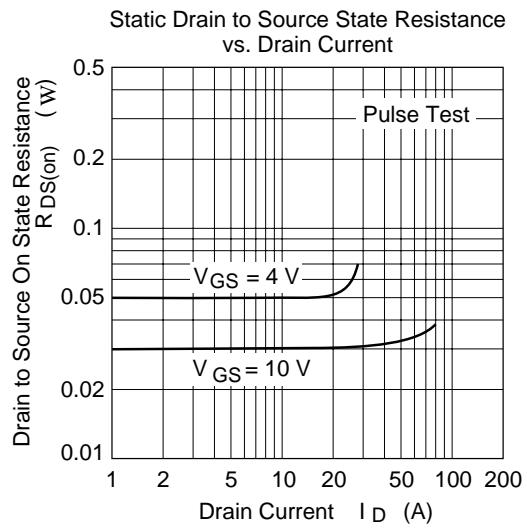
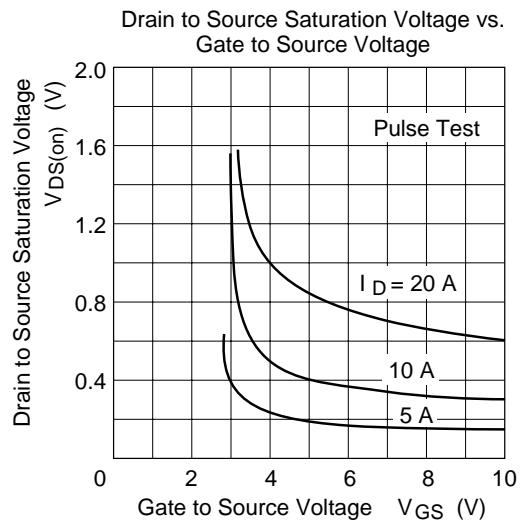
Note: 3. Pulse test

4. Include the time shift based on increasing of channel temperature when operate under over load condition.

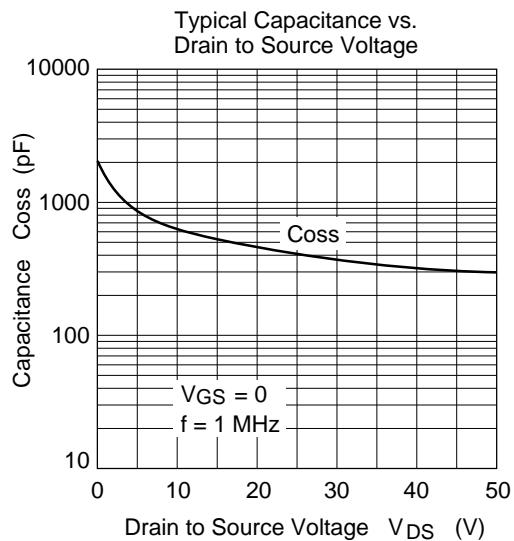
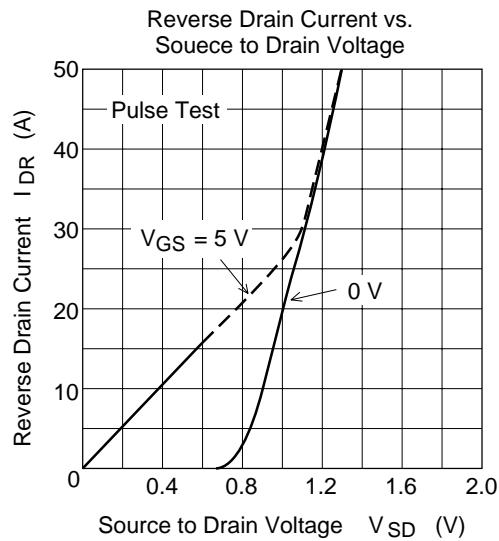
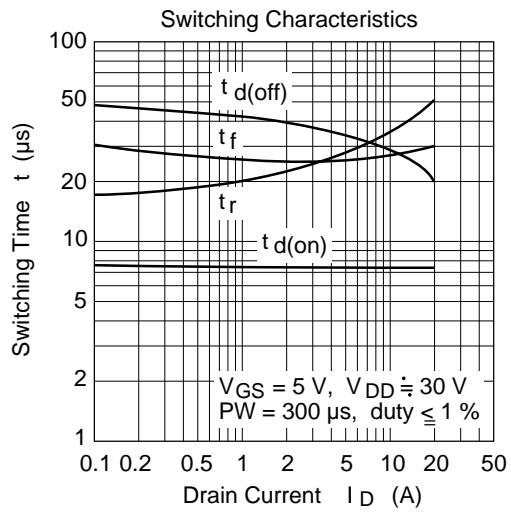
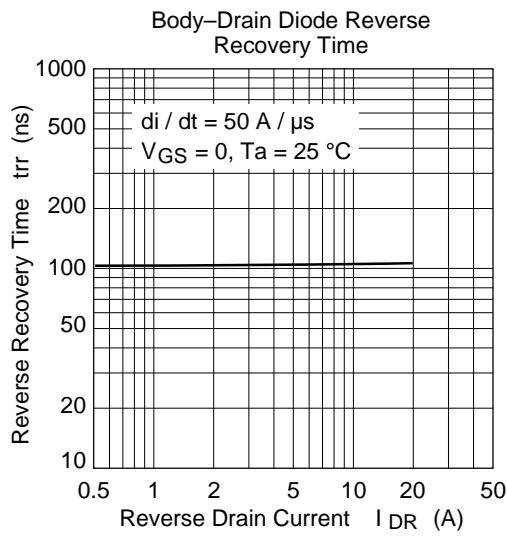
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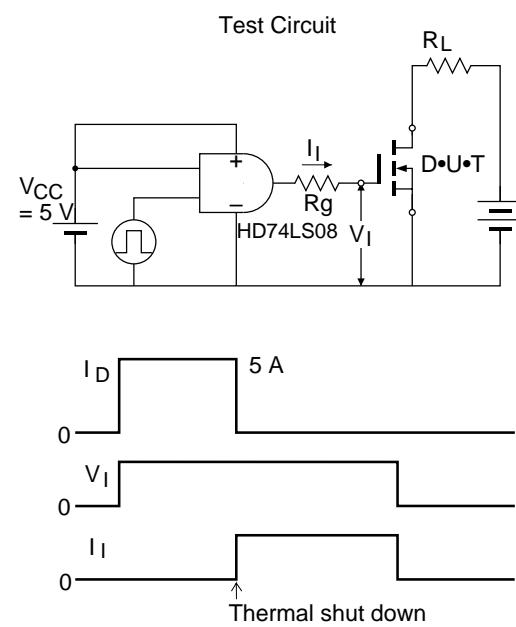
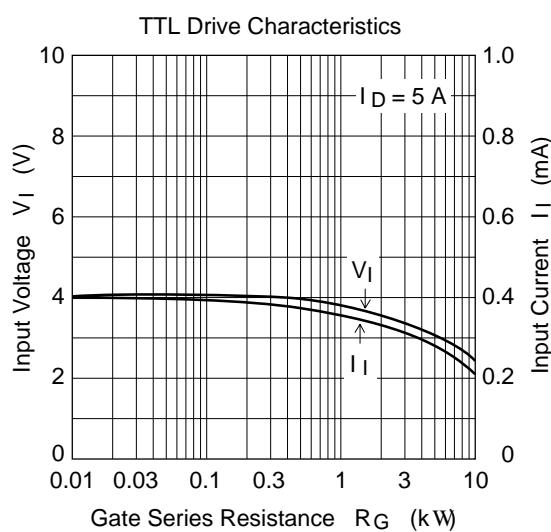
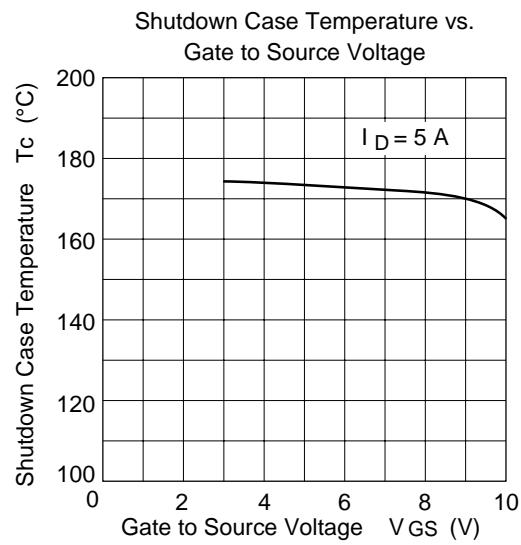
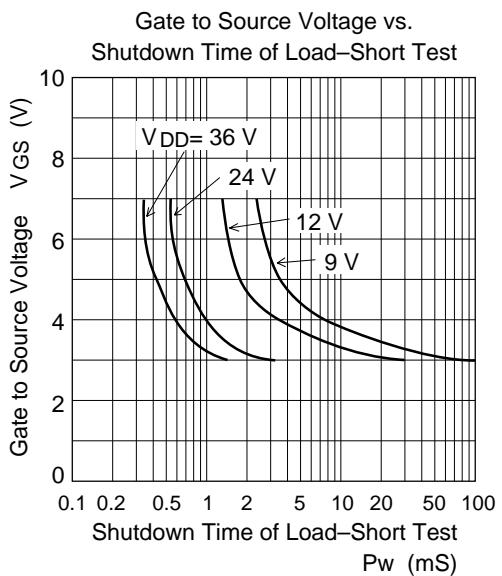
Main Characteristics



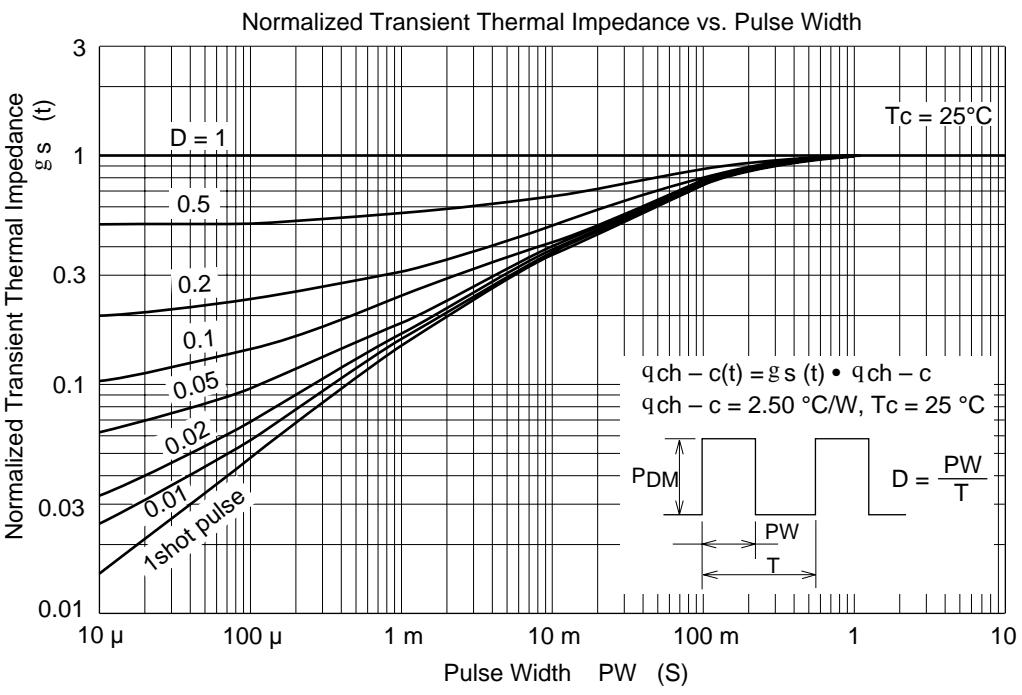


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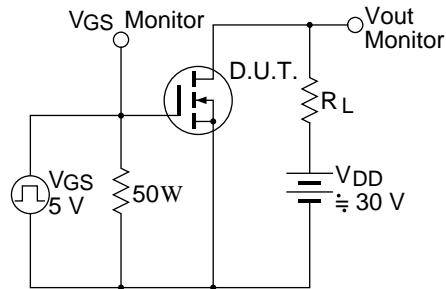




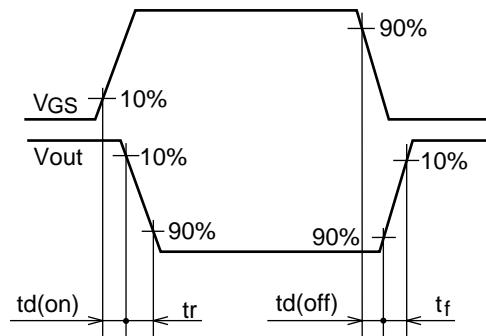
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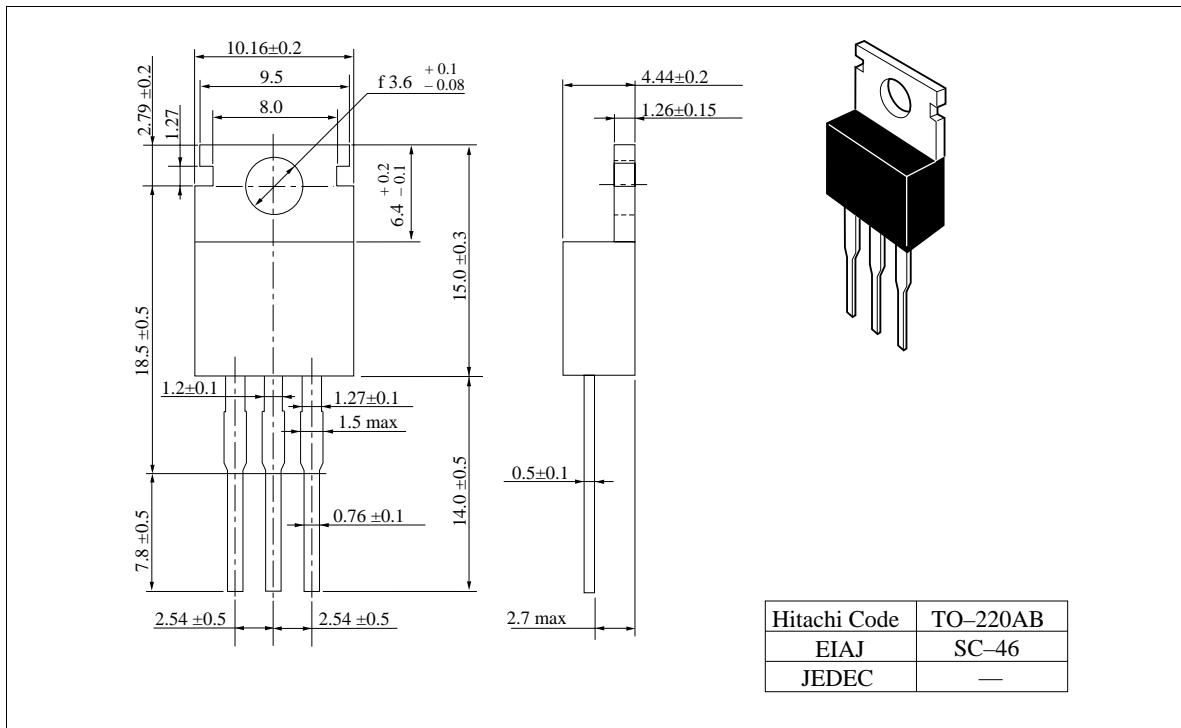


Switching Time Test Circuit



Waveform



Package Dimensions**Unit: mm**

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